



# iPLDLV22V10-15 LOW VOLTAGE, HIGH PERFORMANCE 10-MACROCELL CMOS PLD

**Low Voltage High-Speed Upgrade to Bipolar 22V10 and CMOS Equivalents**

- Supply Voltage Range 3.0V to 3.6V
- $t_{PD}$  15 ns, 50 MHz with Feedback, 83.3 MHz with No Feedback
- Max  $I_{CC}$  = 35 mA
- 12 Dedicated Inputs and 10 I/O Pins
- 10 Macrocells with Programmable I/O Architecture (Register/Combinatorial)
- Variable P-terms—Up to 16 per Macrocell, Selectable Output Polarity, Separate Output Enable P-term
- Global Asynchronous Clear and Synchronous Preset P-terms
- 1-Micron CHMOS III E PROM Technology
- Programmable "Security Bit" Allows Total Protection of Proprietary Designs
- 100% Generically Tested Logic Array
- Available in 300-mil 24-Pin PDIP and 28-Pin PLCC Packages

(See Packaging Spec., Order Number 240800, Package Type N and P)

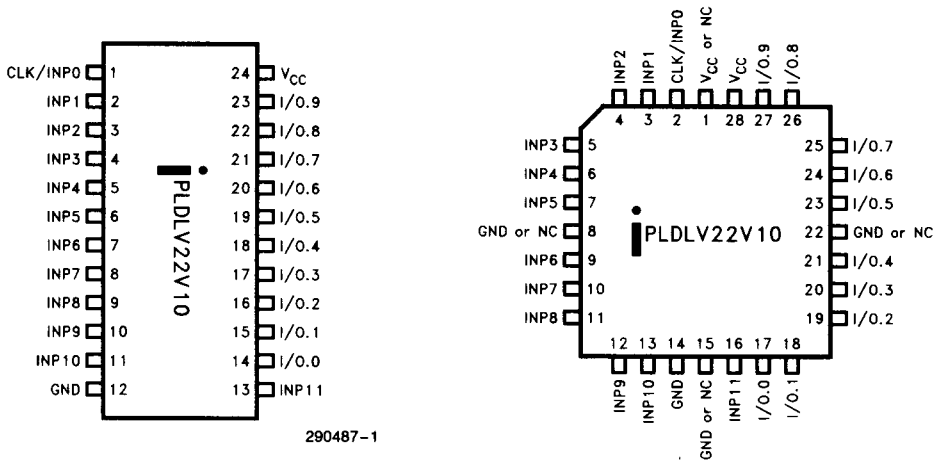


Figure 1. Pinout Diagrams

## INTRODUCTION

The iPLDLV22V10 is a low voltage, high-performance, high-integration, general-purpose CMOS PLD and operates at 3.3V core logic and I/O. The iPLDLV22V10 accommodates logic functions with up to 22 inputs and 10 I/O macrocells. I/O macrocells include an average of 12 p-terms for input, with a separate p-term for output enable. Figure 2 shows the global architecture of the device.

## JEDEC AND PIN COMPATIBILITY

The iPLDLV22V10 is 100% JEDEC-, pin- and function-compatible with the industry-standard 22V10 PLD. JEDEC files developed for 22V10 devices can be used to program the iPLDLV22V10. When the N PLDLV22V10 (28-pin PLCC) is used to replace a conventional 22V10 in an existing design socket, pins 8, 15, 22 and 1 are left as No Connects (NC). New designs can take advantage of the additional device  $V_{CC}$  and grounds these pins offer.

## PROGRAMMABLE MACROCELLS

In addition to the 12 dedicated input pins, the iPLDLV22V10 contains 10 programmable macrocells. Each of the macrocells can be programmed to function as an input or as a combinatorial or registered output. Programmable output polarity and programmable feedback options allow the iPLDLV22V10 to be tailored to the precise needs of the target application. Figure 3 shows the architecture of each macrocell.

### Output Polarity

The output polarity for each iPLDLV22V10 macrocell is programmable. Each combinatorial or registered output can be active-high or active-low.

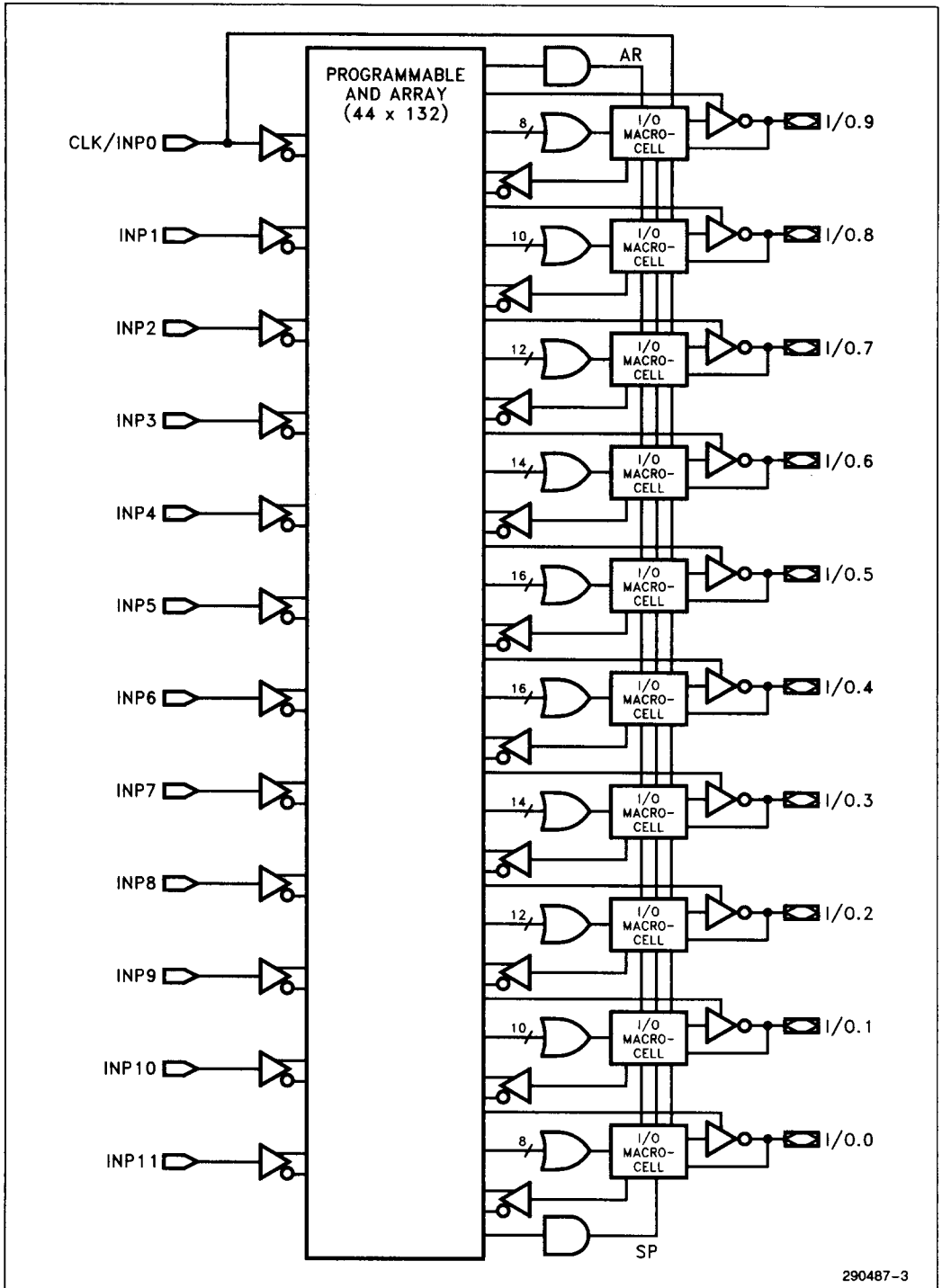
### Feedback Options

iPLDLV22V10 macrocells programmed as combinatorial outputs support pin feedback to the logic array (i.e., feedback from the I/O pin). iPLDLV22V10 macrocells programmed as registers allow internal register feedback to the logic array.

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## ORDERING INFORMATION

$f_{CNT1}$ (MHz)	$f_{MAX}$ (MHz)	$t_{PD}$ (ns)	Order Code	Package	Operating Range
50	83.3	15	P PLDLV22V10-15	PDIP	Commercial
			N PLDLV22V10-15	PLCC	Commercial



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Figure 2. IPLDLV22V10 Global Architecture

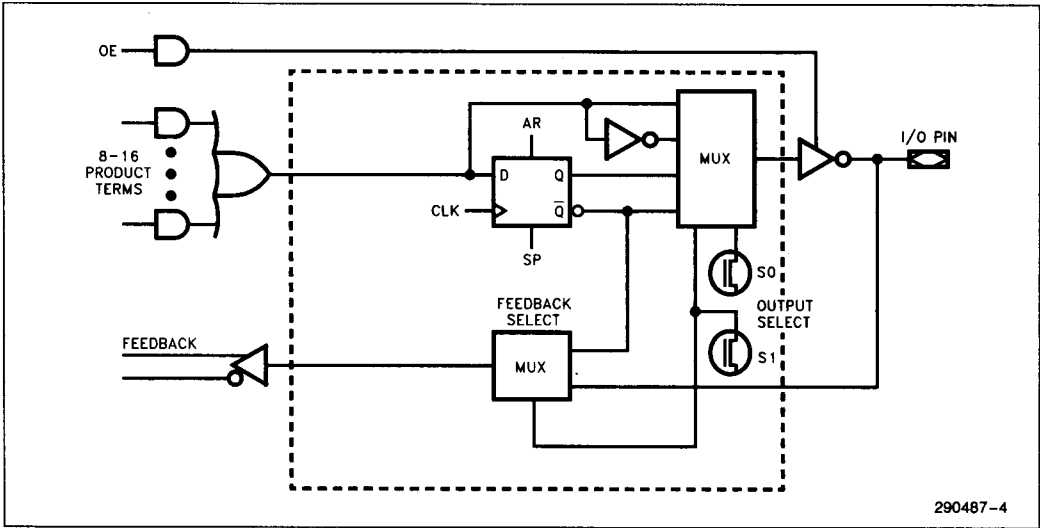


Figure 3. IPLDLV22V10 Macrocell Architecture

Table 1 lists the macrocell configurations:

Table 1. IPLDLV22V10 Macrocell Configurations

S1	S0	Output/Polarity	Feedback
0	0	Registered/Active Low	Registered
0	1	Registered/Active High	Registered
1	0	Combinatorial/Active Low	Pin
1	1	Combinatorial/Active High	Pin

**Register Preset/Reset**

iPLDLV22V10 macrocell registers can be preset or reset using global preset and reset p-terms. Register preset is synchronous and must meet the specified setup time to the clock signal. Register reset is asynchronous and has no setup requirement to the clock. Preset and reset set or reset the register. Output polarity is selected separately.

**Programmable Output Enable**

Each macrocell contains an output buffer that can place the respective output in a high-impedance state (three-state). The output buffer is controlled by a single p-term per macrocell in the logic array and is asynchronous.

**POWER-ON CHARACTERISTICS**

iPLDLV22V10 inputs and outputs begin responding 1 μs (max.) after V<sub>CC</sub> power-up (V<sub>CC</sub> = 3.0V) or after a power-loss/power-up sequence. All macrocells programmed as registers are set to a logic low.

## PROGRAMMING CHARACTERISTICS

Prior to programming, all EPROM logic array cells are in the "connected" state. The macrocells by default are configured for registered output, active-low operation with registered feedback.

### Intelligent Programming Algorithm

The iPLDLV22V10 supports the Intelligent Programming Algorithm, a fast, reliable algorithm for programming many types of Intel programmable devices.

## PROCESS TECHNOLOGY

The iPLDLV22V10 is fabricated on Intel's CHMOS EPROM process. Over 20 million devices (including EPROMs and Microcontrollers) have been fabricated on this process.

## TESTABILITY

The iPLDLV22V10 is completely tested at the factory. Unlike fuse-based PLDs, which have one-time programmable fuse links that limit testing to small-scale sampling, each EPROM cell in the iPLDLV22V10 is tested and erased prior to shipment.

## SECURITY

A single programmable bit, called the security bit or verify protect bit, controls access to the data programmed into the device. Once this security bit is set, the design cannot be copied.

Since data in the device is stored in EPROM cells, the contents of the device cannot be read even with

microscopic examination, providing an additional level of design security not available with fuse-based devices.

## DEVELOPMENT SOFTWARE

### Third Party Support

The iPLDLV22V10 is supported by choosing the standard 22V10 from third-party logic compilers such as ABEL\*, CUPL\*, PLDesigner\*, Log/IC, etc. Programming support is provided by third-party programmer companies such as Data I/O, Logical Devices, STAG, etc. Please refer to the "Third-Party Support" lists in the *Programmable Logic* handbook for complete information and vendor contacts.

### PLDshell Plus

Full logic compilation and functional simulation for the iPLDLV22V10 is supported by PLDshell Plus software by choosing the PLD22V10 option on the programming menu.

PLDshell Plus design software is Intel's new, user-friendly design tool for PLD design. PLDshell Plus allows users to incorporate their preferred text editor, programming software, and additional design tools into a easy-to-use, menued design environment that includes Intel's PLDasm logic compiler and simulation software along with disassembly, conversion, and translation utilities. The PLDasm compiler and simulator software accepts industry-standard PDS source files that express designs as Boolean equations, truth tables, or state machines. On-line help, datasheet briefs, technical notes, and error message information, along with waveform viewing/printing capability make the design task as easy as possible. PLDshell Plus software is available from Intel Literature channels or from your local Intel sales representative, order #611942.

\*ABEL is a trademark of Data I/O Corp. CUPL is a trademark of Logical Devices, Inc. PLDesigner is a trademark of MINC, Inc. Log/IC is a trademark of ISDATA, Corporation.

**ABSOLUTE MAXIMUM RATINGS\***

Supply Voltage ( $V_{CC}$ ) <sup>(1)</sup> .....	-2.0V to +7.0V
Programming Supply Voltage ( $V_{PP}$ ) <sup>(1)</sup> .....	-2.0V to +13.5V
D.C. Input Voltage ( $V_I$ ) <sup>(1, 2)</sup> ...	-0.5V to $V_{CC} + 0.5V$
Storage Temperature ( $T_{stg}$ ) .....	-65°C to +150°C
Ambient Temperature ( $T_A$ ) .....	-10°C to +85°C

NOTICE: This is a production data sheet. The specifications are subject to change without notice.

*\*WARNING: Stressing the device beyond the "Absolute Maximum Ratings" may cause permanent damage. These are stress ratings only. Operation beyond the "Operating Conditions" is not recommended and extended exposure beyond the "Operating Conditions" may affect device reliability.*

**RECOMMENDED OPERATING CONDITIONS**

Symbol	Parameter	Min	Max	Units
$V_{CC}$	Supply Voltage	3.0	3.6	V
$V_{IN}$	Input Voltage	0	$V_{CC}$	V
$V_O$	Output Voltage	0	$V_{CC}$	V
$T_A$	Operating Temperature	0	+70	°C

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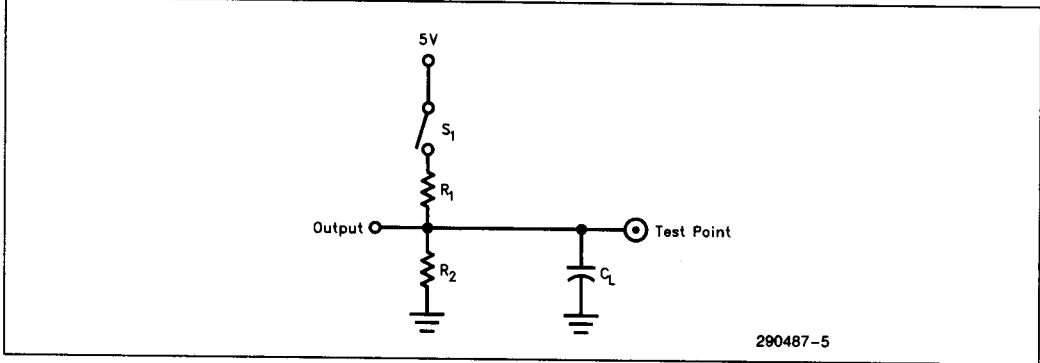
**D.C. CHARACTERISTICS** ( $T_A = 0^\circ\text{C}$  to  $+70^\circ\text{C}$ ,  $V_{CC} = 3.3V \pm 10\%$ )

Symbol	Parameter	Min	Typ	Max	Units	Test Conditions
$V_{IH}^{(3)}$	High Level Input Voltage	2.0		$V_{CC} + 0.3$	V	
$V_{IL}^{(3)}$	Low Level Input Voltage	-0.6		0.8	V	
$V_{OH}$	TTL High Output Voltage	2.4			V	$V_{CC} = 3.0V$ $I_{OH} = -0.4\text{ mA}$
	CMOS High Output Voltage	$V_{CC} - 0.3$			V	$I_O = -100\text{ pA} = V_{CC}\text{ Min}$
$V_{OL}$	Low Level Output Voltage			0.5	V	$I_O = 16\text{ mA D.C.}, V_{CC} = \text{Min}$
$I_I$	Input Leakage Current			10	$\mu\text{A}$	$V_{CC} = \text{Max.}, \text{GND} < V_{IN} < V_{CC}$
$I_{OZ}$	Output Leakage Current			10	$\mu\text{A}$	$V_{CC} = \text{Max.}, \text{GND} < V_{OUT} < V_{CC}$
$I_{SC}^{(4)}$	Output Short Circuit Current			120	mA	$V_{CC} = \text{Max.}, V_{OUT} = 0.5V$
$I_{CC}$	Power Supply Current			35	mA	$V_{CC} = 3.6V$

**NOTES:**

1. Voltages with respect to GND.
2. Minimum D.C. input is -0.5V. During transitions, the inputs may undershoot to -2.0V or overshoot to +7.0V for periods of less than 20 ns under no load conditions.
3. Absolute values with respect to device GND; all over and undershoots due to system or tester noise are included.
4. Not more than 1 output should be tested at a time. Duration of that test should not exceed 1 second.

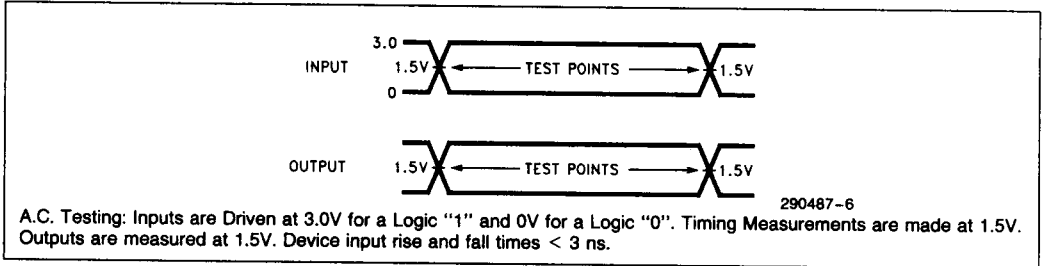
**A.C. TESTING LOAD CIRCUIT**



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Specification	S <sub>1</sub>	C <sub>L</sub>	Commercial		Measured Output Value
			R <sub>1</sub>	R <sub>2</sub>	
t <sub>PD</sub> , t <sub>CO</sub>	Closed	50 pF	240Ω	160Ω	1.5V
t <sub>PZX</sub>	Z → H: Open Z → L: Closed				1.5V
t <sub>pxz</sub>	H → Z: Open L → Z: Closed	5 pF			H → Z: V <sub>OH</sub> - 0.5V L → Z: V <sub>OL</sub> + 0.5V

**A.C. TESTING INPUT, OUTPUT WAVEFORM**



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A.C. Testing: Inputs are Driven at 3.0V for a Logic "1" and 0V for a Logic "0". Timing Measurements are made at 1.5V. Outputs are measured at 1.5V. Device input rise and fall times < 3 ns.

**CAPACITANCE** (T<sub>A</sub> = 0°C to 70°C; V<sub>CC</sub> = 3.3V ± 10%)(5)

Symbol	Parameter	Min	Typ	Max	Units	Conditions
C <sub>IN</sub>	Input Capacitance		5	8	pF	V <sub>IN</sub> = 0V, f = 1.0 MHz
C <sub>IO</sub>	I/O Capacitance		6	8	pF	V <sub>OUT</sub> = 0V, f = 1.0 MHz
C <sub>CLK</sub>	CLK Capacitance		15	17	pF	V <sub>OUT</sub> = 0V, f = 1.0 MHz

**COMBINATORIAL MODE A.C. CHARACTERISTICS**
 $(T_A = 0^\circ\text{C to } +70^\circ\text{C}, V_{CC} = 3.3\text{V} \pm 10\%)(6)$ 

Symbol	Parameter	IPLDLV22V10-15			Units
		Min	Typ	Max	
$t_{PD}^{(7)}$	Input or I/O to Output Valid—w/10 Outputs Switching	6		15	ns
$t_{PZX}^{(8)}$	Input or I/O to Output Enable	6		15	ns
$t_{PXZ}^{(8)}$	Input or I/O to Output Disable	6		15	ns
$t_{CLR}$	Input or I/O to Asynch. Reset			20	ns

**NOTES:**

5. These values are evaluated at initial characterization and whenever design modifications occur that may affect capacitance.

6. Typical values are at  $T_A = +25^\circ\text{C}$ ,  $V_{CC} = 3.3\text{V}$ .

7. Ten outputs switching.

8.  $t_{PZX}$  and  $t_{PXZ}$  are measured at  $\pm 0.5\text{V}$  from steady state voltage as driven by spec. output load.  $t_{PXZ}$  is measured with  $C_L = 5\text{ pF}$ .  $Z \rightarrow H$  and  $Z \rightarrow L$  are measured at 1.5V on output.

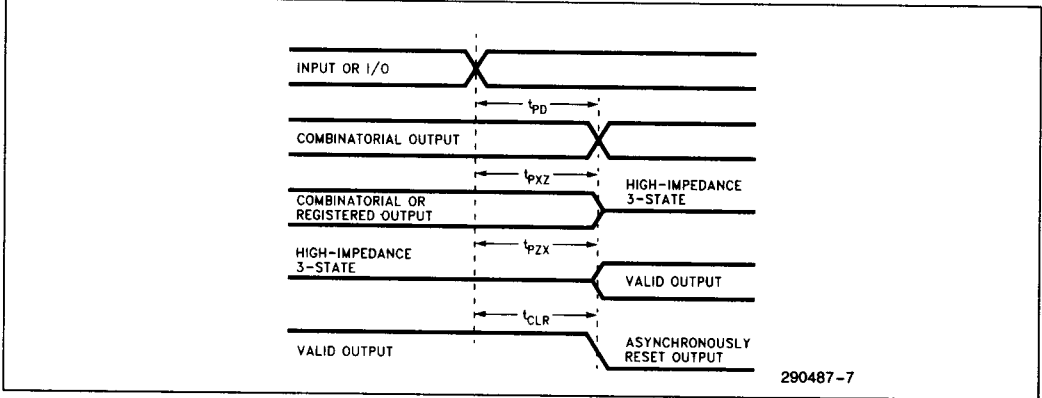
9. Measured with device configured as a 10-bit counter.


**REGISTER MODE—SYNCHRONOUS CLOCK A.C. CHARACTERISTICS**
 $(T_A = 0^\circ\text{C to } +70^\circ\text{C}, V_{CC} = 3.3\text{V} \pm 10\%)(6)$ 

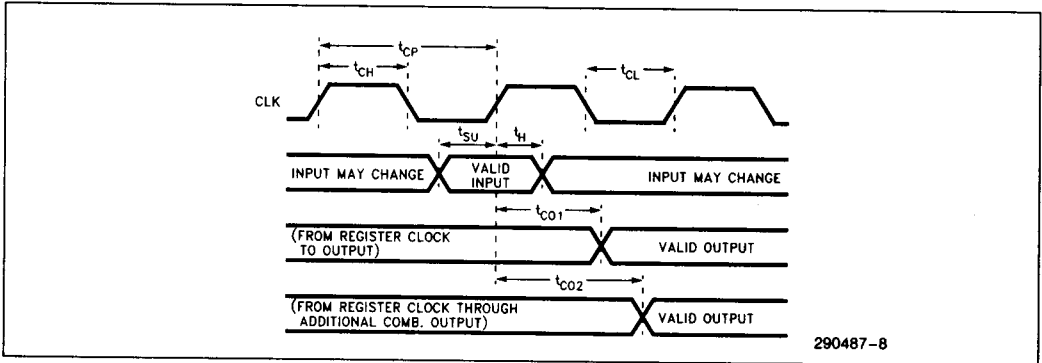
Symbol	Parameter	IPLDLV22V10-15			Units
		Min	Typ	Max	
$f_{CNT1}^{(7)}$	Max. Counter Frequency $1/(t_{SU} + t_{CO})$ —External Feedback	50	60		MHz
$f_{CNT2}^{(7)}$	Max. Counter Frequency $1/t_{CNT}$ —Internal Feedback	83.3	95		MHz
$f_{MAX}$	Max. Frequency (Pipelined) $1/t_{CP}$ —No Feedback	83.3	95		MHz
$t_{SU}$	Input or I/O Setup Time to CLK	3			ns
$t_{SP}$	Input or I/O Setup Time to Synchronous Preset	10			ns
$t_H$	Input or I/O Hold Time from CLK	0			ns
$t_{CO1}$	CLK to Output Valid	3		10	ns
$t_{CO2}$	CLK to Output Valid Fed Through Combinatorial Macrocell			18	ns
$t_{CNT}$	Register Output Feedback to Register Input—Internal Path			12	ns
$t_{CL}$	CLK Low Time	5			ns
$t_{CH}$	CLK High Time	5			ns
$t_{CP}$	CLK Period	12			ns
$t_{arw}$	Asynchronous Reset Pulse Duration	5			ns
$t_{arr}$	Asynchronous Reset to CLK $\uparrow$ Recovery Time	10			ns



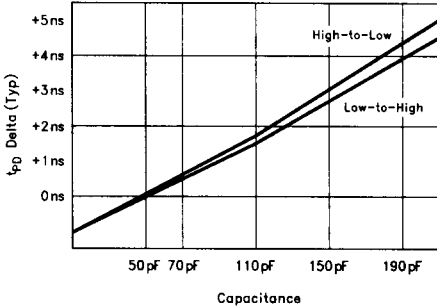
**COMBINATORIAL MODE**



**SYNCHRONOUS REGISTERED MODE**



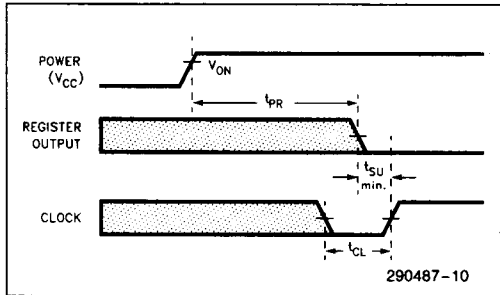
**$t_{PD}$  Derating vs Capacitive Loading**



Conditions:  
 $T_A = 70^\circ C$   
 $V_{CC} = 4.75V$

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**POWER-UP RESET**



290487-10

**POWER-UP RESET CHARACTERISTICS**

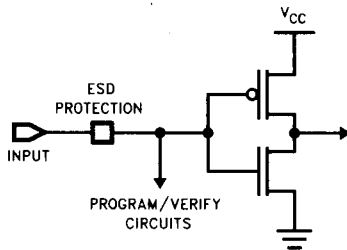
Parameter Symbol	Parameter Description	Value
$t_{PR}$	Power-Up Reset Time	1000 ns Max.
$V_{ON}$	Turn-On Voltage	2.5V

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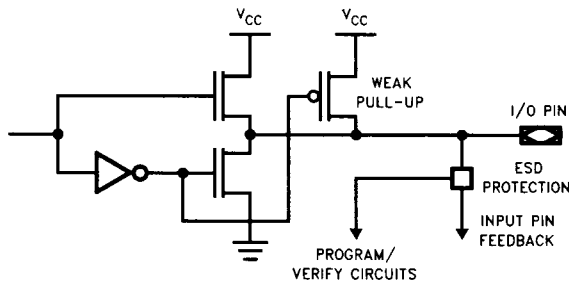
**POWER-UP RESET**

Internal power-up reset circuits ensure that all flip-flops will be reset to a logic 0 after the device has powered up. Because  $V_{CC}$  rise can vary significantly from one application to another,  $V_{CC}$  rise must be monotonic.

**Input/Output Equivalent Schematics**



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